Fluctuation-Induced Tunneling Conductivity in Nanoporous TiO$_2$ Thin Films

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**ABSTRACT:** The electronic mechanisms responsible for dark conductivity in nanoporous TiO$_2$ thin films remain only partially understood, although they control the efficiency of charge transport in a wide range of technological applications. Measurements in the 78–335 K temperature range show DC conductivity values spanning over 4 orders of magnitude, with a high-temperature Arrhenius dependence that gradually changes into a temperature-independent plateau at low temperatures. We show evidence that a fluctuation-induced tunneling conductivity (FITC) mechanism is fully consistent with the experimental data. Quantitative agreement is demonstrated for the entire temperature range ($T = 78–335$ K) with a FITC model parametrized according to atomistic models of nanoporous TiO$_2$ and the characterization of the films by X-ray diffraction and scanning electron microscopy measurements. These findings suggest that dark DC conductivity in nanoporous TiO$_2$ films depends strongly on the properties of the junctions linking the constituent nanoparticles.

**SECTION:** Electron Transport, Optical and Electronic Devices, Hard Matter

Nanoporous TiO$_2$ thin films have attracted considerable attention due to their pivotal role in energy conversion and environmental applications, including photovoltaics, photocatalysis and remediation of hazardous waste, electrochromic windows and displays, and chemical sensors. However, the underlying mechanisms responsible for electron transport through nanoporous TiO$_2$ remain only partially understood even though they often determine a limiting factor in device performance. Here, we address the mechanism responsible for dark DC conductivity in TiO$_2$ thin films under vacuum conditions. We find that a fluctuation-induced tunneling conductivity (FITC) mechanism is supported by experimental data for a wide temperature range.

In recent years, there have been significant contributions toward understanding charge transport in nanoporous titania thin films. The most popular models include variable-range hopping (VRH) and/or multiple trap and release (MTR) of electrons in an electrically homogeneous medium containing a distribution of traps. These models have been particularly successful when applied to the conductivity of photogenerated electrons at temperatures experimentally accessible in a native device environment. However, they predict a temperature ($T$) dependence of the dark DC conductivity of the form $\sigma \propto T^{-\alpha}$, where $\alpha = 1$ in the MTR model and $\alpha = 1/4$ for VRH. As shown in Figure 1, such a dependence does not account for the observed saturation of dark conductivity at low temperature, as reported here and elsewhere. In contrast, the FITC model offers a proper description of conductivity over the entire temperature range with a single set of structural parameters, predicting not only the Arrhenius high-temperature behavior but also the temperature-independent tunneling regime at low temperature.

Because the model can be closely tied to the nanoporous film microstructure, it should provide valuable insight for the development of high-performance electrode materials.

FITC models have been extensively applied to a variety of systems with heterogeneous microstructures, including carbon...
polyvinylchloride films, polycarbonate composite films containing microcrystalline charge-transfer complexes, tin-doped indium oxide nanoparticle films, microcrystalline silicon, and carbon nanotube bundles. Here, we propose FITC to model the dark DC conductivity of TiO$_2$ thin films prepared by sintering nanoparticles as found in solar cells or environmental applications. The model predicts temperature-independent conductivity at low temperatures, reflecting simple inelastic tunneling, and a gradual transition to exponential Arrhenius-type (linear in $\ln \sigma$ versus $1/T$) behavior at high temperature, as observed in experiments (see Figure 1).

For typical TiO$_2$ thin-film dimensions and preparation conditions, the asymptotic low-temperature conductivity is very small ($\sigma \approx 10^{-13} \, \Omega^{-1} \, \text{cm}^{-1}$) and therefore difficult to measure. In fact, most conductivity measurements reported to date have been limited to the high-temperature regime where the Arrhenius-type behavior predicted by the FITC model is indistinguishable from models based solely on thermally activated processes. It is therefore not surprising that the FITC mechanism has been largely overlooked. In this Letter, we address dark DC conductivities over a wide temperature range ($T = 78–335 \, \text{K}$). In addition to the high sensitivity measurements of electrical conductivity, we characterize the samples by scanning electron microscope (SEM) images (see Figure 2), powder X-ray diffraction (XRD) measurements, and atomistic modeling to provide insight into the microstructure and electrically heterogeneous nature of the TiO$_2$ thin films closely tied to the FITC mechanism. These structural data are essential to build a charge-transport model that takes into account the barriers for electron transport through the nanoparticle contact junctions.

Fluctuation-Induced Tunneling Conduction Model. Building upon FITC models previously applied to describe conductivity in other systems of comparable microstructure, we model the TiO$_2$ thin films as networks of contact junctions where noncrystalline TiO$_2$ regions connect the crystalline anatease centers of TiO$_2$ nanoparticles (see the SEM images in Figure 2 and the representations depicted in Figure 3). The tunneling rate across a junction depends on the effective area $A$ at the region of closest approach between crystallites, the effective tunneling width $w$ of the noncrystalline region of the junction, and the zero-field barrier height $\varphi_{00}$ which is primarily the result of the conduction band offset between the crystalline and noncrystalline TiO$_2$ phases.

With typical junction parameters (e.g., $A \approx 50 \, \text{nm}^2$, $w \approx 3–4 \, \text{nm}$; see Table 1) and a static dielectric constant of $\varepsilon_r \approx 40$ inside of the junction, the effective junction capacitance $C = \varepsilon_r \varepsilon_0 A / w$ is very small (on the order of $10^{-6} \, \text{pF}$). Therefore, thermal fluctuations in the density of the free electrons near the junction generate strong voltage fluctuations $V_T$ with $\langle V_T^2 \rangle = k_B T/C$, where $k_B$ is the Boltzmann constant. Upon averaging, these fluctuations can increase the tunneling probability by effectively reducing the width and height of the barrier due to the superposition of the applied and thermally generated electric fields (see Figure 3). Note that the resulting Boltzmann distribution $P(\nu') = (\nu'/\pi k_B T)^{1/2} \exp(-\nu'^2/(k_B T))$ of thermally generated electric field fluctuations $\nu' = V_T/w$ has a width related to the charging energy $E_C = CV_T^2/2 = a\nu'^2$ required to displace the capacitor from equilibrium, where $a = \varepsilon_r \varepsilon_0 A w / 2$.

The resulting fluctuation-induced tunneling conductivity of the TiO$_2$ thin film is

$$\sigma(\nu') = \frac{\gamma (\nu') A}{rV}$$

(1)
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fi in the direction of the applied electric field and a back
time and a forward current density component in the direction of

The dimensionless parameters \( \xi \) and \( \eta \) are field
dependent and originate from the first two terms in a power
series expansion of the exponent of the transmission coefficient
under the WKB approximation.\(^3\)

Both the Arrhenius and temperature-independent regimes in
the observed fluctuation-induced tunneling conductivity are
described by eq 2. Each of the four terms in curly brackets
includes a forward current density component in the direction of
the applied electric field and a backflow current density in the
opposite direction. The first term is the net current density in the
low-temperature limit, with an abrupt change in the density of
states at the Fermi energy, while the other terms are corrections
obtained by expanding the Fermi–Dirac distribution to first
order in temperature. The second term corresponds to the
correction to the density of occupied states below the Fermi
energy. The third term is the net current density due to electrons
in the exponential tail of the distribution above the Fermi energy
that are higher in energy than \( \phi_0 \) and are assumed to have a
transmission coefficient equal to 1 (i.e., thermal activation over
the barrier). The last term in curly brackets is the net current
density of electrons at energies above the Fermi energy with a
transmission coefficient less than 1 (i.e., thermally activated
tunneling).

Experimental Methods. Anatase nanoparticles were obtained
from Sigma–Aldrich Corporation and Ishihara Corporation
with diameters of \(<25 \text{ and } 7 \text{ nm}, \) respectively. TiO\(_2\) (1.5 g)
was added to 1.3 mL of water, followed by sonication for 15 min.
For the conductivity measurements, the nanoparticle slurry was
spread onto a bottom electrode between two fiberglass spacers,
which were \(200 \pm 4 \mu \text{m} \) thick with a measured resistance
\(>200 \Omega. \) Immediately thereafter, the top electrode was applied,
the excess slurry was removed, and the sample was dried for 24 h
at \(\sim 70 ^\circ \text{C}. \) Dried samples were annealed at \(450 ^\circ \text{C}\) for 1 h,
the typical sintering conditions used for DSSCs. The sample
delectrodes were high-chromium-content stainless steel (grade 309).
Samples for electrical measurements were lightly clamped with
grade 309 bolts to maintain constant sample-to-electrode contact
during the measurement and eliminate the effects of thermal
expansion. The samples were loaded in a cryostat (Janis ST-100)
and kept in the dark under vacuum (<20 mTorr) for more than
24 h prior to measurements. A Stanford Research Systems SR570
low-noise current preamplifier was used to supply a 4 V bias and
measure the current. To quantify the contact resistance in our
devices, we varied the thickness of the TiO\(_2\) nanoparticle films.
We found that the use of chromium-rich stainless steel as the
contact surface minimizes both the oxide layer formed on the
electrode during sintering and the corresponding contact resistance,
which is negligible compared to the resistance of the TiO\(_2\)
film. The films for the XRD (Bruker D8 with Cu K\(\alpha\) radiation)
and SEM characterization were prepared by doctor blading the
TiO\(_2\)/water slurry on glass and FTO/glass substrates, respec-
tively. The nanocrystallite diameters reported in Table 1 were
determined by applying Scherrer’s semiempirical formula to the
(101) Bragg peak.

Atomistic Structure Modeling. An atomistic model of the
contact junctions connecting TiO\(_2\) nanoparticles was obtained
by sintering anatase nanoparticles using annealing molecular
dynamics simulations, after thermalization of the system at
\(450 ^\circ \text{C}. \) Simulations were performed by using the LAMMPS
package\(^3\) in the NVT ensemble with the temperature main-
tained at 450 °C using a Nosé–Hoover thermostat with a
damping time of 10 fs. The atomic positions and velocities were
updated using the velocity-Verlet algorithm with a time step of

Table 1. Nanocrystallite Diameter \( d_{nc} \) Measured by XRD and
FITC Model Fitting Parameters Used for Samples A and B in
Figure 1\(^a\)

<table>
<thead>
<tr>
<th>( d_{nc} ) (nm)</th>
<th>( \phi_0 ) (meV)</th>
<th>( w ) (nm)</th>
<th>( A ) (nm(^2))</th>
<th>( d_i ) (nm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>A</td>
<td>17.0</td>
<td>421</td>
<td>3.45</td>
<td>71.6</td>
</tr>
<tr>
<td>B</td>
<td>15.9</td>
<td>388</td>
<td>3.73</td>
<td>22.5</td>
</tr>
</tbody>
</table>

\(^a\) \( A, w, \) and \( \phi_0 \) are the effective area, width, and zero-field barrier height
of the junction, respectively, and \( d_i \) is the effective junction diameter given
by \( d_i \approx 2(A/\pi)^{1/2}. \)

\[
\begin{align*}
\langle j'_\xi \rangle &= \frac{m_n q^2 T^2}{2 \hbar^2} \left\{ e^{-\frac{2 \omega \xi q^2}{k_B T}} \left( 1 - e^{-T \eta q^2 / k_B T} \right) \right. \\
&+ \left. \left( e^{-\frac{2 \omega \xi q^2}{1 + T}} - 1 \right) e^{-T \eta q^2 / k_B T} \right\} \\
&+ \left( e^{-\frac{2 \omega \xi q^2}{1 + T}} - 1 \right) e^{-T \eta q^2 / k_B T} \\
&+ \left( e^{-\frac{2 \omega \xi q^2}{1 + T}} - 1 \right) e^{-T \eta q^2 / k_B T} \\
&- \left( 1 - e^{-T \eta q^2 / k_B T} \right) \left( \phi_0 + q^2 (w / k_B T) e^{-T \eta q^2 / k_B T} \right) \right. \\
&\left. \left. \right\} \right\} \right. \\
\end{align*}
\]

where \( t \) is the thickness of the sample, \( V \) is the voltage across
the junction, \( \gamma \) is the sheet-conductance proportionality constant,\(^3\)
and \( \langle j'_\xi \rangle \) is the thermal average of the net current density \( j'_\xi \)
in the direction of the applied field.

Figure 4. (a) Molecular dynamics simulation results of two 4 nm
particles sintered at 450°C. (b) Cylindrical sample cut from (a) showing
the crystalline anatase core and noncrystalline shell of the nanoparticles.
(c) Average atomic rmsd relative to bulk anatase.
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The activated high-temperature regime (\(T > 250 \text{ K}\)) and the temperature-independent regime (\(T < 150 \text{ K}\)). Figure 1 also shows the limitations of VRH and MTR models. 40 Note that the FITC model agrees with the dark DC conductivity data over the entire temperature range, including both the high- and low-temperature regimes, while the VRH and MTR models can only account for one of these regimes with a unique set of parameters.

The effective zero-field barrier heights of 0.42 and 0.39 eV extracted from the conductivity measurements using the FITC model for samples A and B, respectively, are comparable to the activation energies \(E_a\) measured for the high-temperature data in this and other works. 22–25 because the slope of \(\ln \sigma\) versus \(1/T\) in this temperature regime is largely determined by \(\phi_0 (\phi_0 \approx E_a)\). Under the MTR model, \(E_a\) is related to the distribution of trap states below the conduction band, which have been attributed to oxygen vacancies, Ti\(^{3+}\) states, and interface states. 22–25,41 \(E_a\) is therefore dependent on measurement and fabrication conditions such as the ambient oxygen pressure and N-doping. 23–25,41 In the FITC model, \(\phi_0\) is due to the conduction band offset at the junction and can also be affected by defect states because they can reduce the effective barrier height for tunneling, though it is the defect states at the contact junction that are relevant. It is worth noting that the low-temperature plateau in the conductivity of sample A is nearly an order of magnitude lower than that of sample B, reflecting both a larger barrier height and a wider tunneling width (see Table 1). Increasing \(\phi_0\) tends to decrease the low-temperature plateau conductivity in addition to increasing the slope of \(\ln \sigma\) versus \(1/T\) in the high-temperature region, while increasing the tunneling width \(\omega\) only reduces the former. 30 In the range of tunnel junction parameters studied, increasing the effective junction area \(A\) increases the conductivity for the entire temperature range studied with negligible effect on the high-temperature slope. Therefore, learning how to optimize \(A\) and control \(\phi_0\) for example, by determining materials that generate lower conduction band offsets or fabrication conditions that optimize the defect distributions at the contact junctions, is of particular interest for technological applications because the conductivity is most sensitive to these parameters at room temperature.

Contact Junction Characterization. Figure 4a shows a representative configuration of two sintered TiO\(_2\) nanoparticles, as obtained by annealing molecular dynamics simulations at 450 °C. A cylindrical sample extracted from these two nanoparticles, shown in Figure 4b, reveals the internal atomic structure with noncrystalline TiO\(_2\) at the contact junction and nanoparticle surface. The analysis of atomic rmsds relative to the anatase crystal structure shown in Figure 4c quantifies the disorder observed in the noncrystalline phase at the junction and extremities of the cylindrical core. These rmsds clearly indicate that the TiO\(_2\) nanoparticles have a noncrystalline shell surrounding the crystalline core. This core–shell structure is consistent with reports of the overall TiO\(_2\) nanoparticle size, obtained from microscopy data, being larger than the nanocrystallite size, determined by XRD. 42 For example, the average particle sizes seen by SEM (see Figure 2) are larger than the nanocrystallite diameter determined from XRD (see Table 1). These results also agree with conductivity measurements of unsintered, spin-coated nanoparticle thin films that display both thermally activated and temperature-independent conductivity regimes, 22,43 suggesting fluctuation-induced carrier tunneling between crystalline cores through noncrystalline shells.

Our molecular dynamics simulations and SEM and XRD data show that tunneling junctions are formed when sintering nanoporous TiO\(_2\) due to its multiphase composition. The junction dimensions are determined by the widths of the noncrystalline regions and the areas of closest approach between nanocrystals. It follows that the barrier heights of the tunneling junctions are due to the energy difference between the conduction band of crystalline anatase and the mobility edge of noncrystalline TiO\(_2\) (see Figure 3). This picture is consistent with the values of \(\phi_0\) for samples A and B extracted from the conductivity measurements using the FITC model. Furthermore, the FITC model is consistent with optical pump/THz probe measurements, providing evidence that, even though the DC conductivity of photoexcited nanocrystalline TiO\(_2\) and ZnO is suppressed relative to bulk values, the AC conductivity is within a factor of 2–4 of the single-crystal DC value. 11,43 These data indicate that the carriers are relatively mobile within a given particle, but their net conductivity is limited by interparticle transport. We note, however, that our observations are limited to vacuum conditions, while the presence of impurities, gas, or an electrolyte at the junctions is expected to have an impact on the shape of the barriers and therefore on the overall conductivity through the nanoparticle network. These effects, of course, have great technological significance and will be the focus of future work. Nevertheless, none of these additional factors are expected to change the underlying transport mechanism through energy barriers at contact junctions.

C. A cylindrical sample extracted from these two nanoparticle thin films can be accurately described by a FITC model. The model is in quantitative agreement with dark DC conductivity measurements over an extended temperature range (\(T = 78–335 \text{ K}\)). The structural parameters extracted from the conductivity data, using the FITC model, are consistent with the characterization of sintered TiO\(_2\) nanoparticle films by SEM, XRD, and annealing molecular dynamics simulations of sintered TiO\(_2\) nanoparticles. These data reveal the formation of noncrystalline regions between the crystalline nanoparticle cores, consistent with energy barriers at the junctions. These findings suggest that improvements in electron transport in emerging technologies based on nanoporous TiO\(_2\) electrodes could be achieved by focusing on ways to optimize the TiO\(_2\) nanoparticle interconnectivity and studying the impact of sintering conditions, particle size and shape, choice of electrolyte, ambient
oxygen and water content, doping, and other fabrication conditions on the dimensions and alignment of electronic energy levels at the interparticle contact junctions.

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**REFERENCES**


(33) There are several studies that consider geometrical narrowing between nanoparticles and its effects on electron trapping in a homogeneous medium,

In Figure 1, the high-temperature conductivity for sample B gives an activation energy of 439 meV and a pre-exponential factor of $7.4 \times 10^{-4} \Omega^{-1} \text{cm}^{-1}$ assuming a thermally activated process (MTR model), while the VRH model gives $\sigma = \sigma_0 \exp\left[-(T_0/T)^{1/4}\right]$ with $\sigma_0 = 1.3 \times 10^{20} \Omega^{-1} \text{cm}^{-1}$ and $T_0 = 7.4 \times 10^9 \text{K}$. 


